

October 2001

FQPF4N90

900V N-Channel MOSFET

General Description

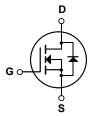
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies.

Features

- 2.5A, 900V, R_{DS(on)} = 3.3 Ω @ V_{GS} = 10 V Low gate charge (typically 24 nC)
- Low Crss (typically 9.5 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQPF4N90	Units
V _{DSS}	Drain-Source Voltage		900	V
I _D	Drain Current - Continuous (T _C = 25°	C)	2.5	А
	- Continuous (T _C = 100)°C)	1.58	А
I _{DM}	Drain Current - Pulsed	(Note 1)	10	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	570	mJ
I _{AR}	Avalanche Current	(Note 1)	2.5	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	4.7	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.0	V/ns
P_{D}	Power Dissipation (T _C = 25°C) - Derate above 25°C Operating and Storage Temperature Range		47	W
			0.38	W/°C
T _J , T _{stg}			-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.66	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Cha	racteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		900			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C			0.9		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 900 V, V _{GS} = 0 V				10	μΑ
		V _{DS} = 720 V, T _C = 125°C				100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$		3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 1.25 A			2.7	3.3	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 50 V, I _D = 1.25 A	(Note 4)		2.6		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			90 9.5	1100 120 12.5	pF pF
	'				0.0	12.0	P.
t _{d(on)}	ng Characteristics Turn-On Delay Time				25	60	ns
t _r	Turn-On Rise Time	$V_{DD} = 450 \text{ V}, I_{D} = 4.2 \text{ A},$			70	150	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25 \Omega$	$R_G = 25 \Omega$		45	100	ns
t _f	Turn-Off Fall Time		(Note 4, 5)		40	90	ns
Q _q	Total Gate Charge	V _{DS} = 720 V, I _D = 4.2 A,			24	30	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 720 \text{ V}, \text{ ID} = 4.2 \text{ A},$ $V_{GS} = 10 \text{ V}$			5.8		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)			11.5		nC
	, , , , , , , , , , , , , , , , , , ,	1				<u> </u>	
	Source Diode Characteristics a		•				1
I _S	Maximum Continuous Drain-Source Diode Forward Current				2.5	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode F					10	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.5 \text{ A}$				1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 4.2 \text{ A},$	(Note: 4)		440		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$	(Note 4)		3.3		μC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 172mH, I_{AS} = 2.5A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq 4.2A, di/dt \leq 200A/µs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300µs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

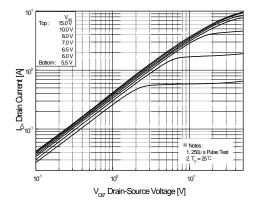


Figure 1. On-Region Characteristics

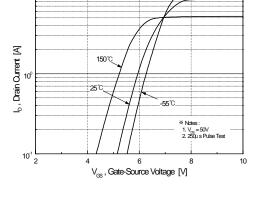


Figure 2. Transfer Characteristics

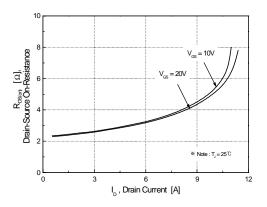


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

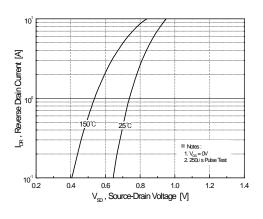


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

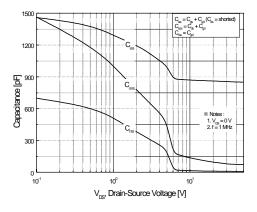


Figure 5. Capacitance Characteristics

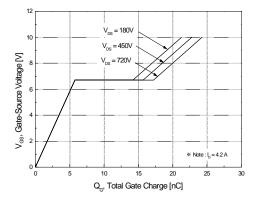
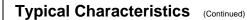


Figure 6. Gate Charge Characteristics



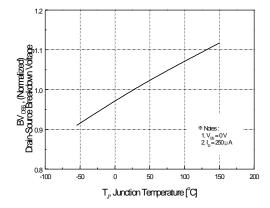
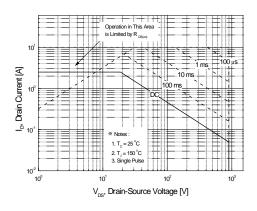


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



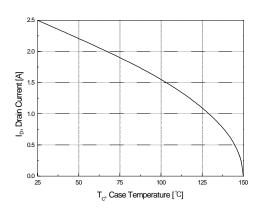


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

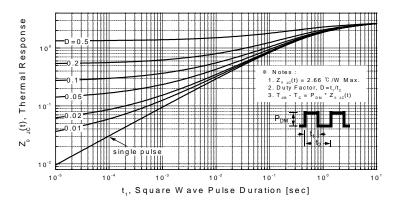
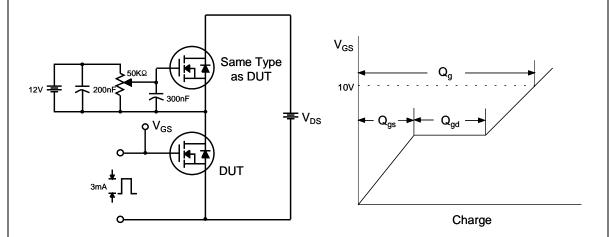
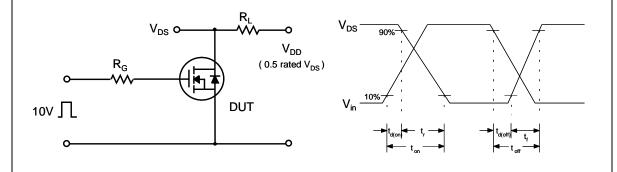


Figure 11. Transient Thermal Response Curve

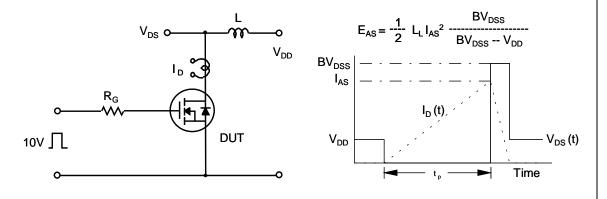
Gate Charge Test Circuit & Waveform



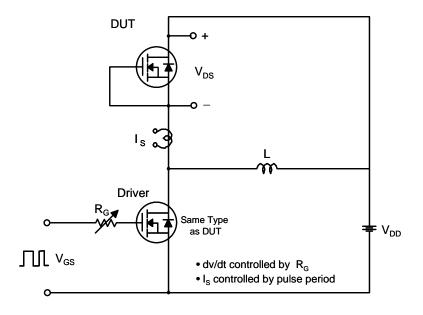
Resistive Switching Test Circuit & Waveforms

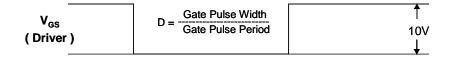


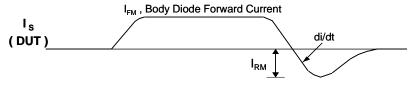
Unclamped Inductive Switching Test Circuit & Waveforms



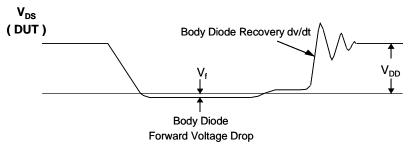
Peak Diode Recovery dv/dt Test Circuit & Waveforms

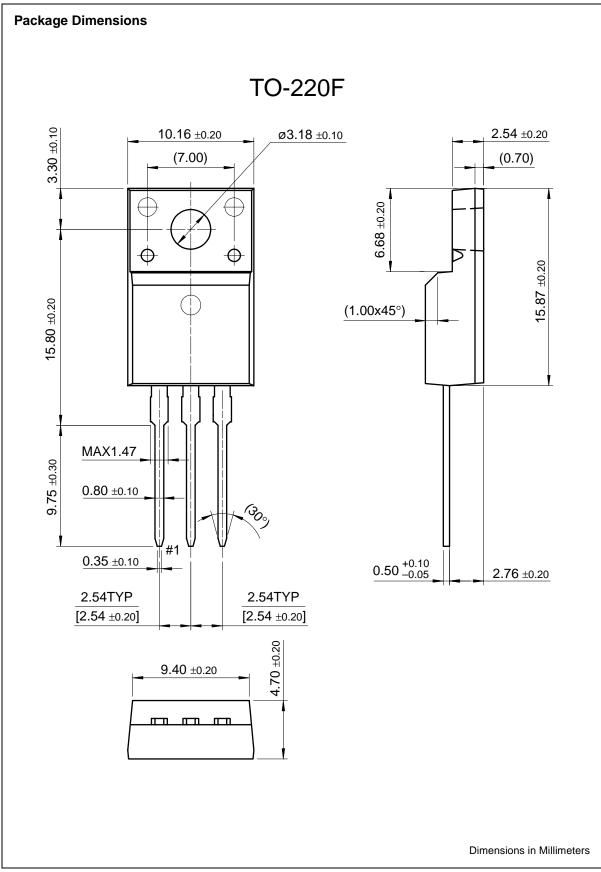






Body Diode Reverse Current





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